What is claimed is:

1. A semiconductor integrated circuit comprising:

a rewritable nonvolatile memory; and

an interface circuit for test,

wherein adjustment data for correcting a change in circuit characteristics which occurs due to variations in electronic parts or devices can be written into said nonvolatile memory via said interface circuit for test.

2. The semiconductor integrated circuit according to claim 1, further comprising:

a terminal for outputting the adjustment data stored in said nonvolatile memory or a value obtained by D/A converting the adjustment data.

3. The semiconductor integrated circuit according to claim 1, further comprising: a microprocessor for control for executing a control in accordance with a command of a program; and a program memory for storing said program executed by the microprocessor,

wherein the adjustment data stored in said nonvolatile memory can be read by said microcomputer.

4. The semiconductor integrated circuit according to claim 1, wherein said electronic part is a quartz oscillator, and said adjustment data is data for adjusting an oscillation frequency of an oscillating

circuit including said quartz oscillator.

5. An electronic system comprising:

an electronic part;

a first semiconductor integrated circuit including:

a first nonvolatile memory, a microprocessor for control for executing a control in accordance with a command of a program, and

a second nonvolatile memory for storing said program executed by the microprocessor, said first nonvolatile memory storing adjustment data for correcting a change in circuit characteristics which occurs due to variations in said electronic parts; and

a substrate over which the electronic part and the first semiconductor integrated circuit being mounted,

wherein said adjustment data stored in said first nonvolatile memory is rewritable.

6. The electronic system according to claim 5, wherein said adjustment data can be written in said first nonvolatile memory via a terminal also serving as a test terminal provided over said substrate.

7. The electronic system according to claim 5, wherein said first semiconductor integrated circuit has an interface circuit for test, and said adjustment data can

be written in said first nonvolatile memory via said interface circuit for test.

8. The electronic system according to claim 5, wherein said second nonvolatile memory is a mask ROM.

9. The electronic system according to claim 5, wherein said electronic part is a quartz oscillator, and said adjustment data is data for adjusting an oscillation frequency of an oscillating circuit including said quartz oscillator.

10. The electronic system according to claim 9, further comprising a second semiconductor integrated circuit in which a device for constructing an oscillating circuit together with said quartz oscillator is formed,

wherein a clock signal generated by said second semiconductor integrated circuit is supplied as a reference clock signal to said first semiconductor integrated circuit.

11. The electronic system according to claim 10, wherein said first semiconductor integrated circuit is a semiconductor integrated circuit for baseband for performing a baseband signal process for communication, and said second semiconductor integrated circuit is a semiconductor integrated circuit for RF having a

transmission/reception function.

12. A semiconductor integrated circuit comprising:

a rewritable nonvolatile memory; and

an interface circuit for test,

wherein adjustment data for correcting a change in circuit characteristics caused by variations in electronic parts or devices, and data peculiar to the semiconductor integrated circuit can be written to said nonvolatile memory via said interface circuit for test.

13. The semiconductor integrated circuit according to claim 12, wherein said electronic part is a quartz oscillator, and said adjustment data is data for adjusting oscillation frequency of an oscillating circuit including said quartz oscillator.